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(54) Title (EN): ANALYSIS DEVICE AND ANALYSIS SYSTEM

(54) Title (FR): DISPOSITIF D'ANALYSE ET SYSTÈME D'ANALYSE

(54) Title (JA): 分析デバイスおよび分析システム

(57) Abstract:

(EN): Provided is an analysis device in which even if a nucleic acid amplification product leaks out of an analysis chip, the occurrence of contamination can be inhibited in an analysis chip which is subsequently set. The analysis device (2) according to the present invention is for analyzing an analysis chip, and is characterized by having an insertion section (202) for the analysis chip, a heating section (91) for the analysis chip, a light source (50) for irradiating the analysis chip with light, a light detection section (60) for detecting light from the analysis chip, and an ultraviolet light irradiation section (70) for the insertion section (202).

(FR): L'invention concerne un dispositif d'analyse dans lequel même si un produit d'amplification d'acide nucléique fuit d'une puce d'analyse, le risque d'une contamination peut être inhibée dans une puce d'analyse qui est ensuite fixée. Le dispositif d'analyse (2) selon la présente invention est destiné à analyser une puce d'analyse, et est caractérisé en ce qu'il comprend une section d'insertion (202) pour la puce d'analyse, une section de chauffage (91) pour la puce d'analyse, une source de lumière (50) pour irradier la puce d'analyse avec de la lumière, une section de détection de lumière (60) pour détecter la lumière provenant de la puce d'analyse, et une section d'irradiation de lumière ultraviolette (70) pour la section d'insertion (202).

(JA): 仮に、分析チップから核酸増幅物が漏出した場合でも、つぎにセットされる分析チップに対するコンタミネーションの発生を抑制できる分析デバイスを提供する。　本発明の分析デバイス(２)は、分析チップを分析する分析デバイスであり、分析チップの挿入部(２０２)、分析チップの加熱部(９１)、分析チップに光を照射する光源(５０)、分析チップからの光を検出する光検出部(６０)、および、挿入部(２０２)に対する紫外線照射部(７０)を有することを特徴とする。

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